

Search Notes

Application/Control No.

10/644,755

Examiner

Anthony Weier

Applicant(s)/Patent under
Reexamination

LORTZ ET AL.

Art Unit

1761

SEARCHED

Class	Subclass	Date	Examiner
426	422	11/22/2006	AW

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor Search	11/22/2006	AW